

Form PTO-1449 U.S. Department of Commerce
Equivalent Patent and Trademark Office

Atty. Docket No. 501.30598CC3
Serial No. (not yet assigned)
Applicant: MORIOKA et al
Filing Date: March 14, 2001
Group:
Page 1 of 2

J1033 U.S. PTO
09/805188
03/14/01

U.S. Patent Documents

| Examiner Initials | Document No. | Date | Name | Class Subclass | Filing Date If Approp. |
|----------------------|-----------------|---------------|-----------------|----------------|---------------------------|
| TN | 3,658,420 | 4/72 | Axelrod | | |
| | 3,771,880 | 11/73 | Bennett | | |
| | 3,930,155 | 12/75 | Kanomata et al | | |
| | 4,332,833 | 6/82 | Aspnes et al | | |
| | 4,376,583 | 3/83 | Alford et al | | |
| | 4,378,159 | 3/83 | Galbraith | | |
| | 4,441,124 | 4/84 | Heebner et al | | |
| | 4,441,268 | 4/84 | Sherman et al | | |
| | 4,448,532 | 5/84 | Joseph et al | | |
| | 4,571,685 | 2/86 | Kamoshida | | |
| | 4,575,922 | 3/86 | Nemiroff | | |
| | 4,614,427 | 9/86 | Koizumi et al | | |
| | 4,806,774 | 2/89 | Lin et al | | |
| | 4,856,904 | 8/89 | Akagawa | | |
| | 4,939,363 | 7/90 | Bando et al | | |
| | 4,963,500 | 10/90 | Cogan et al | | |
| | 5,004,307 | 4/91 | Kino et al | | |
| | 5,028,778 | 7/91 | Ninomiya et al | | |
| | 5,055,679 | 10/91 | Ninomiya et al | | |
| | 5,172,000 | 12/92 | Scheff et al | | |
| 5,274,434 | 12/93 | Morioka et al | | | |
| TN | 5,276,498 | 1/94 | Galbraith et al | | |

Foreign Patent Documents

| Document No. | Date | Country | Class Subclass | Translation Yes No |
|-----------------|------|---------|----------------|-----------------------|
| TN 59-65428 | 4/84 | Japan | | |
| TN 1257725 | 9/86 | USSR | | |

Form PTO-1449
Equivalent

U.S. Department of Commerce
Patent and Trademark Office

Atty. Docket No. 501.30598CC3
Serial No. (not yet assigned)
Applicant: MORIOKA et al
Filing Date: March 14, 2001
Group:
Page 2 of 2

Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

TN "Simultaneous Observations of Partially Oxidized...", Komiya et al, J. Vac. Sci. Technology, Vol. 12, No. 1, Jan/Feb 1975

TN "Scanning Laser Senses Wafer Defects", Electronics, Mar. 16, 1978, Vol. 51, No. 6, pp. 48 and 50, Copy 356/237

Examiner

Date Considered

TN 8/11/01

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.